

# Ion energies in EUV induced plasma: Measuring methods

*Citation for published version (APA):* Ven, van de, T. H. M., Beckers, J., Osorio, E. A., Banine, V. Y., & Kroesen, G. M. W. (2014). *Ion energies in* EUV induced plasma: Measuring methods. Poster session presented at 17th Euregional Workshop on the Exploration of Low Temperature Plasma Physics (WELTPP 2014), Kerkrade, Netherlands.

Document status and date: Published: 01/01/2014

## Document Version:

Publisher's PDF, also known as Version of Record (includes final page, issue and volume numbers)

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17th WORKSHOP ON THE EXPLORATION OF LOW TEMPERATURE PLASMA PHYSICS (WELTPP), Conference Center Rolduc, Kerkrade, November 20-21, 2014 Technische Universiteit Eindhoven University of Technology

# Ion energies in EUV induced plasma: **Measuring methods**

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## Ionization by Extreme Ultra-Violet photons

By exposure to high energy photons gasses can be ionized to form a plasma. In this research Extreme Ultra-Violet (EUV) light is used to induce a plasma in low pressure gas mixtures. Understanding these plasmas is important for industrial applications such as EUV lithography.

Plasma produced in free space Photon energy: 92 eV Wavelength: 13.5 nm Pulse duration: ~ 150 ns Ionization degree: < 0.1 % Low pressure monoatomic and molecular gasses and mixtures



EUV transmission as function of pressure <sup>1</sup>



# Retarding Field Energy Analyzer (RFEA)

The RFEA probe measures ion fluxes discriminated by energy. Measurements made in the past showed the IEDF for low energy ions (< 10 eV) but lacked the resolution to detect the small fluxes of high energy ions.



# **Research questions**

The plasma creation is not yet fully understood. Questions we have so far include:

- What happens with the remaining photon energy after ionization?
- Which processes create excited species?
- Why is the emission confined to the EUV beam path?
- What is the influence of plasma-wall and EUV-wall interactions?

# Plasma composition and energy distributions

Simulations have been made in the past to predict plasma composition and ion energy distribution functions (IEDF)<sup>5</sup>. High energy ions (> 20 eV) are expected but have not been measured yet.

The electron density has been measured by Van der Horst<sup>4</sup> which can be used for a global model. In pure hydrogen the photoionization creates mostly H<sub>2</sub><sup>+</sup> ions which is readily converted to  $H_3^+$ .



The development of concentrations in a hydrogen plasma according to a basic global model.

RFEA and EQP will be used to measure time resolved plasma properties.

## **Electrostatic Quadrupole Plasma (EQP) Mass** Spectrometer

Simultaneous measurement of ion energy and mass makes it possible to resolve the IEDF for individual ion species.



Schematic of the EQP 5

G<sub>2</sub>: potential sweep to discriminate ion energies

There are also optical techniques under consideration.

<sup>1</sup>B.L. Henke, E.M. Gullikson and J.C. Davis, At. Data Nucl. Data Tables, 54(2) (1993) <sup>2</sup>Í. Doğan and E. Osorio (2014) <sup>3</sup>D.I. Astakhov and V.V. Ivanov (2014) 4 R.M. van der Horst et. al., J. Phys. D: Appl. Phys., 47(30) (2014) <sup>5</sup> Hiden Analytic LTD., Warrington, England, http://www.hidenanalytical.com/



/ Department of Applied Physics